


<b>Search Notes</b>  	<b>Application/Control No.</b>  10771590	<b>Applicant(s)/Patent Under Reexamination</b>  CHEN ET AL.
	<b>Examiner</b>  DAVID Y ENG	<b>Art Unit</b>  2455

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES			
Search Notes	Date	Examiner	
update	1/15/2009	de	

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
709	213	1/15/2009	de

--	--